

MOSFET FIGURES OF MERIT

(1)

Let's consider a MOSFET n-type with source and bulk shorted to ground while the gate is biased at $V_G > V_T$. The drain is biased with $V_D > 0$. In the channel we have

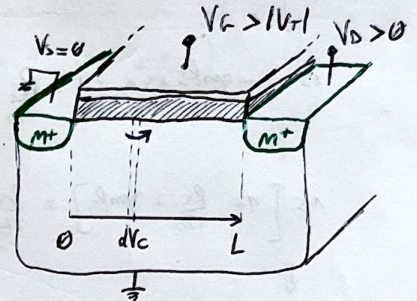
$$dV_C = I_{DS} \cdot dR = I_{DS} \cdot \frac{dx}{q n \mu_n W \Delta} = I_{DS} \cdot \frac{dx}{Q'_n(x) \mu_n W}$$

where $Q'_n(x) = C'_{ox} (V_G - V_C - V_T)$

$$\int_0^{V_{DS}} W \mu_n C'_{ox} (V_G - V_C - V_T) dV_C = \int_0^L I_{DS} dx$$

$$I_{DS} = \mu_n C'_{ox} \frac{W}{L} \left[(V_G - V_T) V_{DS} - \frac{V_{DS}^2}{2} \right]$$

$$I_{DS}^{SAT} = \frac{1}{2} \mu_n C'_{ox} \frac{W}{L} (V_{GS} - V_T)^2$$



For $V_{DS} \text{ when } > V_{DS}^{SAT} = (V_{GS} - V_T)$ the previous relation is no more valid. At steady state the current being the same is equal to the one reaching the drain side, so the drift velocity (and the electric field) must increase as we move towards the drain, i.e. $n \downarrow$ and $n \cdot v \approx \text{CONSTANT}$. In the point called PINCH-OFF we have $Q'_n = 0$ (negligible) and it is expected to use backwards as V_{DS} moves above V_{DS}^{SAT} , which is the area behind the pinch-off point the previous relation is still valid, so

$$I_{DS}^{SAT'} = K' \frac{W}{L'} (V_G - V_T)^2 \quad \left[K' = \frac{1}{2} \mu_n C'_{ox} \right]$$

where $L' < L$, so $I_{DS}^{SAT'} > I_{DS}^{SAT}$. Assuming that $(L - L')$ remains small, as suggested by the experimental I-V curves, we get that

$$I_{DS} = I_{DS}^{SAT} + \left(\frac{\partial I_{DS}}{\partial V_{DS}} \right) \bigg|_{V_{DS} = V_{DS}^{SAT}} \cdot (V_{DS} - V_{DS}^{SAT})$$

where

$$\frac{\partial I_{DS}}{\partial V_{DS}} = \frac{\partial I_{DS}^{SAT}}{\partial L} \frac{\partial L}{\partial V_{DS}^{SAT}} = - \frac{I_{DS}^{SAT}}{L} \cdot \frac{\partial L'}{\partial V_{DS}} \bigg|_{V_{DS} = V_{DS}^{SAT}}$$

so

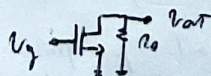
$$I_{DS} = I_{DS}^{SAT} \left[1 + \lambda (V_{DS} - V_{DS}^{SAT}) \right] \quad \left(\lambda = - \frac{1}{L} \frac{\partial L'}{\partial V_{DS}} \bigg|_{V_{DS} = V_{DS}^{SAT}} \right)$$

We define $\frac{1}{\lambda} = V_A$ EARLY VOLTAGE.

Does not depend on current!

→ GAIN

The maximum gain of a MOSFET is $g_{m,ro} = \mu = \frac{\partial I}{\partial V_A} \cdot \frac{V_A}{I} = \frac{\partial V_A}{\partial V_{DS}}$



②

RESISTANCES

• (R_D)

$$v_o = i_s \cdot R_S$$

$$i_s = -g_m v_o + \frac{v_s - v_o}{r_o}$$

↓

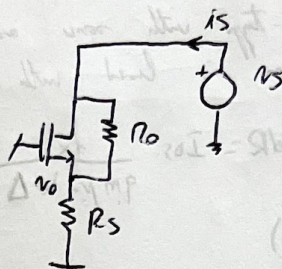
$$i_s = -g_m R_S i_s + \frac{v_s}{r_o} - \frac{R_S}{r_o} i_s$$

↓

$$i_s \left[1 + \frac{R_S}{r_o} + g_m R_S \right] = \frac{v_s}{r_o}$$

↓

$$\frac{v_s}{i_s} = r_o + R_S + g_m R_S r_o = r_o + R_S [1 + g_m r_o]$$



• (R_S)

$$v_o = i_s \cdot R_D$$

$$i_s = g_m v_T + \frac{v_T - v_o}{r_o}$$

↓

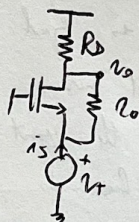
$$i_s = -\frac{R_D}{r_o} i_s + \frac{v_T}{r_o} + g_m v_T$$

↓

$$v_T \left[g_m + \frac{1}{r_o} \right] = i_s \left[1 + \frac{R_D}{r_o} \right]$$

↓

$$\frac{v_T}{i_s} = \frac{1 + \frac{R_D}{r_o}}{\frac{1}{r_o} + g_m} = \frac{r_o + R_D}{1 + g_m r_o}$$



WEAK INVERSION

In this regime electrons are not dominating the electrostatics in the channel, so the holes are almost flat. The concentration of electrons at the same node is computed by using the M-B statistics

$$n(x) = N_s \cdot e^{-\frac{q\phi_B}{kT}}$$

big $\phi_B = V_{GS} - \psi_s$. The unit is due to diffusion!

$$I_m = q D_n \frac{dn}{dx} = q D_n \frac{n(x)}{L} = q D_n \frac{n_i^2}{L N_A} e^{-\frac{q\phi_B}{kT}}$$

It can be shown that

$$I_{DS} = 4n \left(\frac{1}{2} \mu_{eff} C_{ox} V_{TH}^2 \right) e^{-\frac{q(V_{GS} - V_{TH})}{kT}}$$

$$(m = 1 + \frac{C_{dep}}{C_{ox}} \approx 1.5)$$

$$\approx \frac{2 I_{DS}}{q V_{GS}} = g_m = \frac{I_{DS}}{n V_{TH}} \quad \text{and} \quad \mu = g_m r_o = \frac{V_A}{n V_{TH}}$$

→ MODERATE INVERSION

EKV model

$$IC = \frac{ID}{4m \left[\frac{1}{2} \mu_n C'_{ox} \frac{W}{L} (V_{TH})^2 \right]}$$

$$gm = \frac{2}{1 + \sqrt{1 + 4 \cdot IC}} \cdot \frac{ID}{m V_{TH}}$$

TAXONOMY	IC	Bias RANGE
WEAK INV.	$IC \leq 0,1$	$V_{DS} \leq V_{TH} - 0,1V$
MODERATE INV.	$0,1 \leq IC \leq 10$	$ V_{TH} - 0,1V \leq V_{DS} \leq V_{TH} + 0,2V$
STRONG INV.	$IC \geq 10$	$V_{DS} \geq V_{TH} + 0,2V$

$$(m = 1 + \frac{C_{dep}}{C'_{ox}} = 1,5)$$

→ CUT-OFF FREQUENCY

Freq. for a unity unit gain

$$\frac{i_{out}}{i_s} = gm R_c$$

$$|P| = \frac{1}{2\pi} \frac{1}{R_c \cdot C_c}$$

↓

$$f_T = gm R_c \cdot \frac{1}{2\pi C_c R_c} = \frac{gm}{2\pi C_c}$$

Assuming that $C_c = C_{gs} \approx C'_{ox} \cdot WL$ then

$$f_T = \frac{2 \cdot \frac{1}{2} \mu_n C'_{ox} \frac{W}{L} V_{ov}}{2\pi C'_{ox} WL} = \frac{1}{2\pi} \frac{\mu_n F}{L} = \frac{1}{2\pi} \frac{v}{L} = \frac{1}{2\pi} \frac{1}{\tau_{DRIFT}}$$

In weak inversion instead, we have that

$$Q' = \frac{q}{2} \cdot n(0) \cdot L \quad [\text{charge per unit area}]$$

$$J_n = q D_n \frac{n(0)}{L} \quad [\text{current density}]$$

$$\tau_{DIFF} = \frac{Q'}{J_n} = \frac{L^2}{2 D_n}$$

$$\text{and } f_T = \frac{1}{2\pi \tau_{DIFF}}$$

$$\tau_{DRIFT} < \tau_{DIFF} \Rightarrow \frac{L^2}{\mu_n V_{ov}} < \frac{L^2}{2 D_n} \Rightarrow V_{ov} > \frac{2 \mu_n kT}{\mu_n q} = (2 V_{TH})$$

